## N-channel TrenchMOS intermediate level FET

Rev. 01 — 7 September 2010

**Product data sheet** 

### 1. Product profile

### 1.1 General description

Intermediate level gate drive N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using advanced TrenchMOS technology. This product has been designed and qualified to the appropriate AEC Q101 standard for use in high performance automotive applications.

### 1.2 Features and benefits

- AEC Q101 compliant
- Suitable for intermediate level gate drive sources

### **1.3 Applications**

- 12 V and 24 V Automotive systems
- Electric and electro-hydraulic power steering
- Motors, lamps and solenoid control

### 1.4 Quick reference data

#### Table 1. Quick reference data

- Suitable for thermally demanding environments due to 175 ℃ rating
- Start-Stop micro-hybrid applications
- Transmission control
- Ultra high performance power switching

Table 1.	Quick reference	uala					
Symbol	Parameter	Conditions		Min	Тур	Max	Unit
$V_{DS}$	drain-source voltage	T <sub>j</sub> ≥ 25 ℃; T <sub>j</sub> ≤ 175 °C		-	-	55	V
I <sub>D</sub>	drain current	V <sub>GS</sub> = 10 V; T <sub>mb</sub> = 25 °C; see <u>Figure 1</u>	<u>[1]</u>	-	-	120	A
P <sub>tot</sub>	total power dissipation	$T_{mb} = 25 $ °C; see Figure 2		-	-	306	W
Static cha	Static characteristics						
R <sub>DSon</sub>	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A};$ $T_j = 25 \text{ C}; \text{ see } Figure 11$		-	2.3	2.7	mΩ



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Table 1.	Quick reference da	tacontinued				
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Avalanch	e ruggedness					
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$\begin{split} I_D &= 120 \text{ A};  \text{V}_{\text{sup}} \leq 55 \text{ V}; \\ R_{\text{GS}} &= 50  \Omega;  \text{V}_{\text{GS}} = 10 \text{ V}; \\ T_{\text{j(init)}} &= 25  \mathbb{C}; \text{ unclamped} \end{split}$	-	-	724	mJ
Dynamic	characteristics					
Q <sub>GD</sub>	gate-drain charge	$I_D = 25 \text{ A}; V_{DS} = 44 \text{ V};$ $V_{GS} = 10 \text{ V}; \text{ see } \underline{\text{Figure } 13};$ $\text{see } \underline{\text{Figure } 14}$	-	75	-	nC

[1] Continuous current is limited by package.

## 2. Pinning information

Table 2.	Pinning	j information		
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		-
2	D	Drain	mb	
3	S	source		
mb	D mounting base; connected to drain			mbb076 S
			SOT404 (D2PAK)	

## 3. Ordering information

Table 3. Ordering i	information		
Type number	Package		
	Name	Description	Version
BUK662R7-55C	D2PAK	plastic single-ended surface-mounted package (D2PAK); 3 leads (one lead cropped)	SOT404

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## 4. Limiting values

#### Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Мах	Unit
V <sub>DS</sub>	drain-source voltage	T <sub>j</sub> ≥ 25 ℃; T <sub>j</sub> ≤ 175 ℃		-	55	V
V <sub>GS</sub>	gate-source voltage	DC	<u>[1]</u>	-16	16	V
		Pulsed	[2]	-20	20	V
I <sub>D</sub>	drain current	$T_{mb}$ = 25 °C; V <sub>GS</sub> = 10 V; see <u>Figure 1</u>	<u>[3]</u>	-	120	А
		$T_{mb}$ = 100 °C; V <sub>GS</sub> = 10 V; see Figure 1	<u>[3]</u>	-	120	А
I <sub>DM</sub>	peak drain current	$T_{mb} = 25 $ °C; $t_p \le 10 \ \mu$ s; pulsed; see <u>Figure 3</u>		-	907	A
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 ℃; see <u>Figure 2</u>		-	306	W
T <sub>stg</sub>	storage temperature			-55	175	C
Tj	junction temperature			-55	175	C
Source-drair	n diode					
ls	source current	T <sub>mb</sub> = 25 °C	<u>[3]</u>	-	120	А
I <sub>SM</sub>	peak source current	$t_p \le 10 \ \mu s$ ; pulsed; $T_{mb} = 25 \ C$		-	907	А
Avalanche ru	uggedness					
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$\label{eq:ld} \begin{array}{l} I_D = 120 \; A; \; V_sup \leq 55 \; V; \; R_GS = 50 \; \Omega; \\ V_GS = 10 \; V; \; T_j(init) = 25 \; {}^\circ\!\!\!\mathcal{C}; \; unclamped \end{array}$		-	724	mJ
E <sub>DS(AL)R</sub>	repetitive drain-source avalanche energy		<u>[4][5][6]</u>	-	-	J

[1] -16V accumulated duration not to exceed 168 hrs.

[2] Accumulated pulse duration not to exceed 5mins.

[3] Continuous current is limited by package.

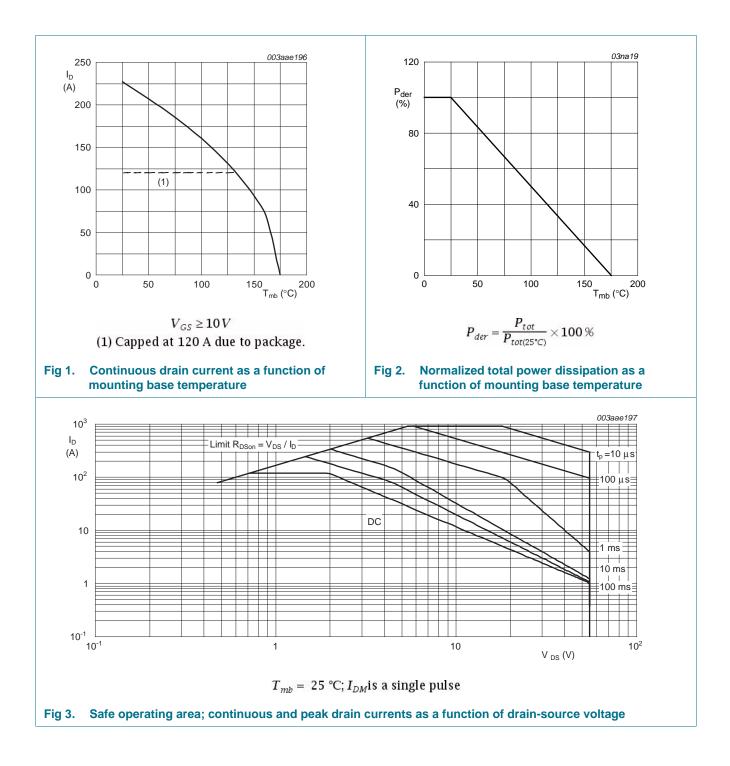
[4] Single-pulse avalanche rating limited by maximum junction temperature of 175 °C.

[5] Repetitive avalanche rating limited by an average junction temperature of 170 °C.

[6] Refer to application note AN10273 for further information.

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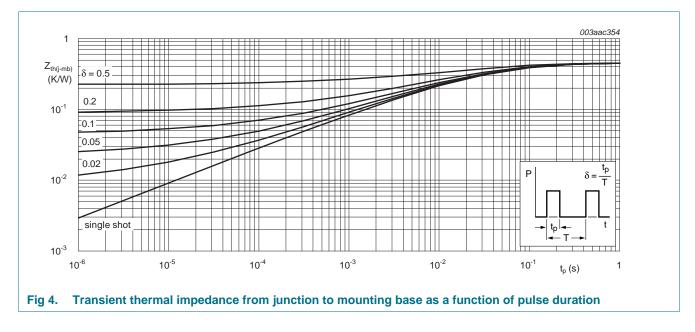
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## 5. Thermal characteristics

Table 5.	Thermal characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R <sub>th(j-mb)</sub>	thermal resistance from junction to mounting base	see Figure 4	-	-	0.45	K/W
R <sub>th(j-a)</sub>	thermal resistance from junction to ambient	vertical in free air	-	60	-	K/W



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## 6. Characteristics

Table 6.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	aracteristics					
V <sub>(BR)DSS</sub>	drain-source	$I_D = 250 \ \mu\text{A}; \ V_{GS} = 0 \ V; \ T_j = 25 \ ^\circ\text{C}$	55	-	-	V
	breakdown voltage	$I_D$ = 250 $\mu A;V_{GS}$ = 0 V; $T_j$ = -55 $^{\circ}\!\!\!\!\!\!C$	50	-	-	V
V <sub>GS(th)</sub> gate-source threst voltage	gate-source threshold voltage	$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 25 \text{ C};$ see <u>Figure 9</u> ; see <u>Figure 10</u>	1.8	2.3	2.8	V
		I <sub>D</sub> = 1 mA; V <sub>DS</sub> = V <sub>GS</sub> ; T <sub>j</sub> = -55 °C; see <u>Figure 10</u>	-	-	3.3	V
		$I_D = 2.5 \text{ mA}; V_{DS} = V_{GS}; T_j = 175 \text{ °C};$ see <u>Figure 10</u>	0.8	-	-	V
I <sub>DSS</sub>	drain leakage current	$V_{DS}$ = 55 V; $V_{GS}$ = 0 V; $T_j$ = 175 °C	-	-	500	μA
		$V_{DS} = 55 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ C}$	-	0.02	1	μA
I <sub>GSS</sub>	gate leakage current	$V_{DS}$ = 0 V; $V_{GS}$ = 20 V; $T_j$ = 25 °C	-	2	100	nA
		$V_{DS} = 0 \text{ V};  V_{GS} = -20 \text{ V};  T_j = 25  \mathfrak{C}$	-	2	100	nA
R <sub>DSon</sub>	drain-source on-state resistance	V <sub>GS</sub> = 5 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 25 ℃; see <u>Figure 11</u>	-	2.9	3.8	mΩ
		V <sub>GS</sub> = 10 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 25 ℃; see <u>Figure 11</u>	-	2.3	2.7	mΩ
		V <sub>GS</sub> = 4.5 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 25 °C; see <u>Figure 11</u>	-	3.2	4.4	mΩ
		V <sub>GS</sub> = 10 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 175 ℃; see <u>Figure 12</u> ; see <u>Figure 11</u>	-	-	6	mΩ
Dynamic	characteristics					
Q <sub>G(tot)</sub>	total gate charge	$I_D = 25 \text{ A}; V_{DS} = 44 \text{ V}; V_{GS} = 5 \text{ V};$ see <u>Figure 13</u> ; see <u>Figure 14</u>	-	146	-	nC
		$I_D = 25 \text{ A}; V_{DS} = 44 \text{ V}; V_{GS} = 10 \text{ V};$	-	258	-	nC
$Q_{GS}$	gate-source charge	see Figure 13; see Figure 14	-	35	-	nC
$Q_{GD}$	gate-drain charge		-	75	-	nC
C <sub>iss</sub>	input capacitance	$V_{GS} = 0 V; V_{DS} = 25 V; f = 1 MHz;$	-	11430	15300	pF
C <sub>oss</sub>	output capacitance	$T_j = 25 $ °C; see Figure 15	-	1100	1320	pF
C <sub>rss</sub>	reverse transfer capacitance		-	772	1060	pF
t <sub>d(on)</sub>	turn-on delay time	$V_{DS}$ = 45 V; $R_L$ = 1.8 $\Omega$ ; $V_{GS}$ = 10 V;	-	61	-	ns
t <sub>r</sub>	rise time	$R_{G(ext)} = 10 \ \Omega$	-	101	-	ns
t <sub>d(off)</sub>	turn-off delay time		-	450	-	ns
t <sub>f</sub>	fall time		-	186	-	ns
L <sub>D</sub>	internal drain inductance	from upper edge of drain mounting base to centre of die ; $T_j = 25 \ \ensuremath{\mathbb{C}}$	-	3.5	-	nH
L <sub>S</sub>	internal source inductance	from source lead to source bond pad ; $T_j = 25 \ \ \ \mathbb{C}$	-	7.5	-	nH

Symbol

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Max

Unit

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Тур

Min

SD	source-drain voltage	I <sub>S</sub> = 25 A; V <sub>GS</sub> = 0 V see <u>Figure 16</u>	'; T <sub>j</sub> = 25 ℃;	-	(	).85	1.2	V
	reverse recovery time	$I_{\rm S} = 20 \text{ A}; dI_{\rm S}/dt = -1$	00 A/µs; V <sub>GS</sub> = 0 V;	-	6	67	-	ns
r	recovered charge	V <sub>DS</sub> = 25 V		-	1	76	-	n
		002000201				(	003aae200	
100		003aae201	100 $10$ $10$ $5/4$	3.	8	-	03888200	
I <sub>D</sub> (A)			(A)					
75			80					
10						V <sub>GS</sub> (V	/) = 3.6	
			60					
50								
			40					
	T <sub>i</sub> = 175 °C	S °C				_	3.4	
25			20					
	///						3.2	
0			0					
0	2 4	6 V <sub>GS</sub> (V)	0 0.5		1	1.5 <sub>V</sub>	2 / <sub>DS</sub> (V)	
		• 65 (•)				•	DS (*)	
	$V_{DS} = 25 \text{ V}$		$T_j$ =	= 25 °C;	$t_p = 30$	0 µs		
iq 5. Tra		in current as a					rrent as	а
	$V_{DS} = 25 \text{ V}$ nsfer characteristics: dra ction of gate-source volta		<i>T<sub>j</sub></i> = Fig 6. Output chara function of d	acterist	ics: dra	in cu		
	nsfer characteristics: dra	age; typical values	Fig 6. Output chara	acterist	ics: dra	in cu oltage	; typica	
250	nsfer characteristics: dra		Fig 6. Output chara function of d	acterist	ics: dra	in cu oltage		
fund	nsfer characteristics: dra	age; typical values	Fig 6. Output chara function of d	acterist	ics: dra	in cu oltage	; typica	
250	nsfer characteristics: dra	age; typical values	Fig 6. Output chara function of d	acterist	ics: dra	in cu oltage	; typica	
250 g <sub>fs</sub> (S)	nsfer characteristics: dra	age; typical values	Fig 6. Output chara function of d	acterist	ics: dra	in cu oltage	; typica	
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250 g <sub>fs</sub> (S) 200	nsfer characteristics: dra	age; typical values	Fig 6.         Output chara function of c           RDSon (mΩ)         16	acterist	ics: dra	in cu oltage	; typica	
250 g <sub>fs</sub> (S) 200	nsfer characteristics: dra	age; typical values	Fig 6.         Output chara function of c           RDSon (mΩ)         16	acterist	ics: dra	in cu oltage	; typica	
250 g <sub>fs</sub> (S) 200 150	nsfer characteristics: dra	age; typical values	Fig 6.         Output chara function of c           RDSon (mΩ)         16           12         12	acterist	ics: dra	in cu oltage	; typica	
250         9           gfs         9           (S)         9           150         100	nsfer characteristics: dra	age; typical values	Fig 6.         Output chara function of c           RDSon (mΩ)	acterist	ics: dra	in cu oltage	; typica	
250 9 <sub>fs</sub> (S) 200 150	nsfer characteristics: dra	age; typical values	Fig 6.         Output chara function of c           RDSon (mΩ)         16           12         12	acterist	ics: dra	in cu oltage	; typica	
func           250         gfs           (S)         200           150         100           50         50	nsfer characteristics: dra	age; typical values	Fig 6. Output chara function of d	acterist	ics: dra	in cu oltage	; typica	
250         9           9fs         9           (S)         9           150         100	nsfer characteristics: dra	003aae199	Fig 6.         Output chara function of c           RDSon (mΩ)	acterist	ics: dra			
fund 250 9fs (S) 200 150 100 50 0	20 40 60	003aae199	Fig 6. Output chara function of $d$	acterist Irain-sc			2003aae202	
fund 250 g <sub>fs</sub> (S) 200 150 100 50 0 0	T <sub>j</sub> = 25 °C; $V_{DS} = 25$	003aae199	Fig 6. Output chara function of $d$	acterist Irain-sc a a a a a a a a a a a a a a a a a a a	ics: dra purce vo	o o o o o o o o o o o o o o o o o o o	20 20 20 20 20 20 VGS (V)	l val
fund 250 9 <sub>fs</sub> (S) 200 150 100 50 0 0 0	20 40 60	003aae199	Fig 6. Output chara function of $d$	acterist Irain-sc acterist Irain-sc acterist act	ics: dra burce vo	o o o o o o o o o o o o o o o o o o o	20 20 20 20 20 20 V <sub>GS</sub> (V) e as a fu	l val

#### Table 6. Characteristics ...continued

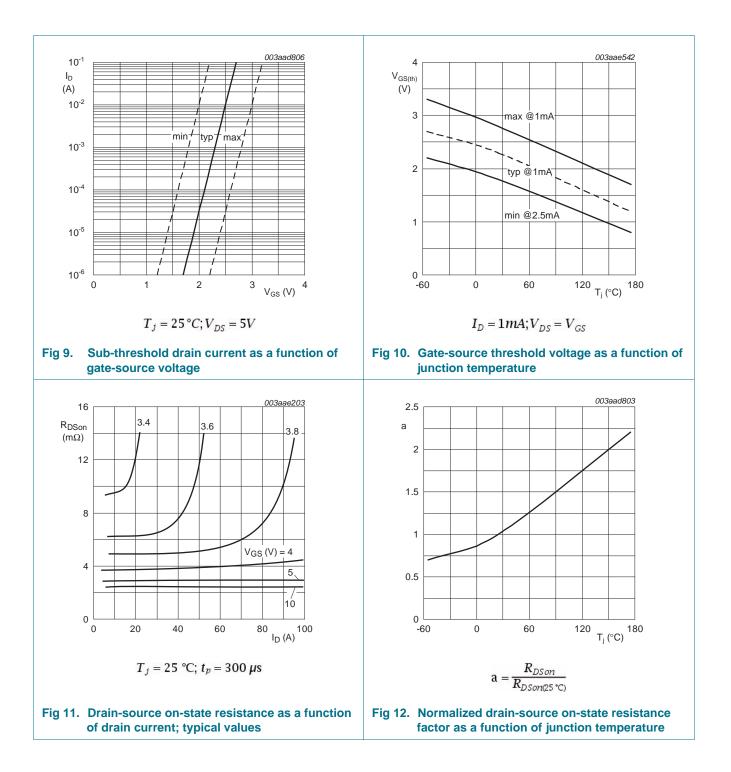
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Conditions

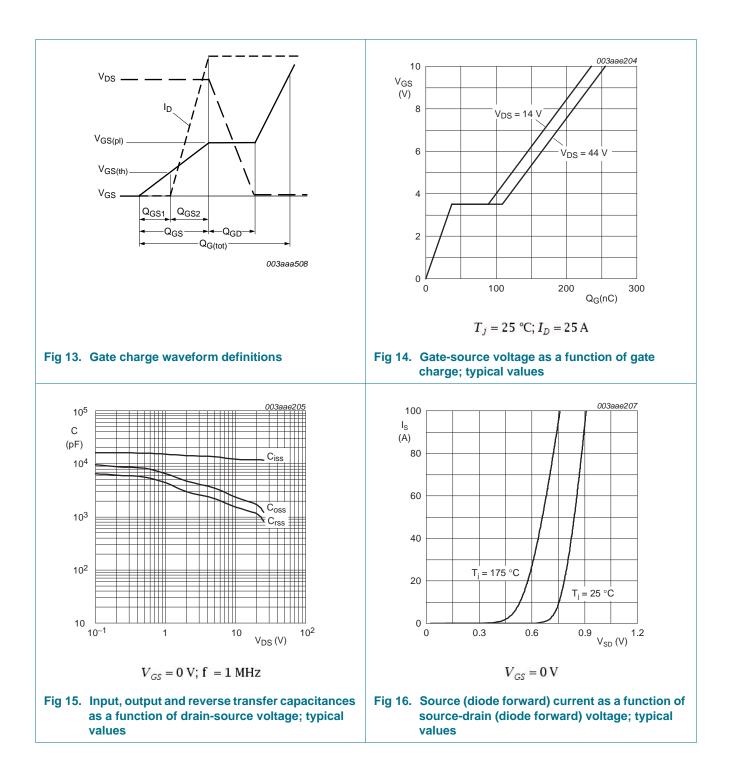
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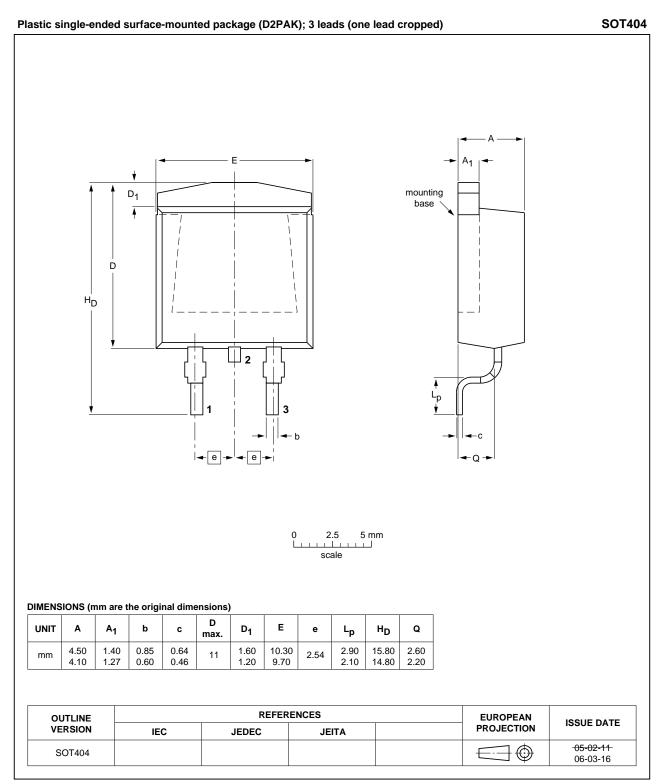


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## 7. Package outline



#### Fig 17. Package outline SOT404 (D2PAK)

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## 8. Revision history

Table 7. Revision h	Revision history						
Document ID	Release date	Data sheet status	Change notice	Supersedes			
BUK662R7-55C v.1	20100907	Product data sheet	-	-			

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### 9. Legal information

### 9.1 Data sheet status

Document status[1][2]	Product status <sup>[3]</sup>	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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Product [short] data sheet	Production	This document contains the product specification.

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